

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination MIYAMOTO ET AL.	
		Examiner Helene Klemanski	Art Unit 1755	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0200385 A1	10-2004	Taguchi et al.	106/031.43
	B	US-2005/0001890 A1	01-2005	Taguchi et al.	347/100
	C	US-2004/0011248 A1	01-2004	Taguchi et al.	106/31.28
	D	US-2004/0189765 A1	09-2004	Taguchi et al.	347/100
	E	US-2004/0080595 A1	04-2004	Taguchi et al.	347/100
	F	US-2004/0194660 A1	10-2004	Taguchi et al.	106/031.43
	G	US-6,039,793 A	03-2000	Gundlach et al.	106/31.28
	H	US-5,980,623 A	11-1999	Hiraoka et al.	106/31.49
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP001378550A1	01-2004	EP	Miyamoto et al.	-----
	O	EP001375608A1	01-2004	EP	Tagushi et al.	-----
	P	EP001473336A1	11-2004	EP	Taguchi et al.	-----
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.